

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: **Spencer M. Gold, et al.**

Serial No.: **Not Yet Assigned**

Filed: **Herewith**

For: **A CONTROLLER FOR MONITORING
TEMPERATURE**

Attorney Docket No.: **SMQ-089/P6550**

Group Art Unit:

Examiner:

BOX PATENT APPLICATION

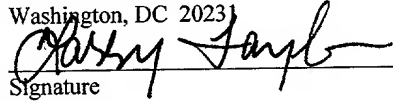
Commissioner for Patents

Washington, D.C. 20231

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Signature

Larry Taylor

Please Print Name of Person Signing

PRELIMINARY AMENDMENT

Dear Sir:

Preliminary to examination of the above-referenced patent application, please
amend the application as follows:

In the Specification:

Please replace the paragraph of page 1, lines 4-7 with the following:

20070519 1007

The present invention relates to five other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548), An Integrated Temperature Sensor (Atty. Docket: SMQ-088/P6549), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).

REMARKS

The above amendment introduces no new subject matter. Entry of the foregoing Preliminary Amendment is in order and requested. If there are any questions regarding the proposed amendment to the application, we invite the Examiner to call Applicants' attorney at the telephone number below.

Respectfully submitted,

LAHIVE & COCKFIELD, LLP



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Date: February 19, 2002

“VERSION WITH MARKINGS TO SHOW CHANGES MADE”

In the Specification:

Please amend the paragraph of page 1 lines 4-7 with the following:

The present invention relates to five [two] other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548[/MDF]), An Integrated Temperature Sensor (Atty. Docket: SMQ-088/P6549[/MDF]), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).